

WHAT IS CLAIMED IS:

1. A microarray comprising a support on which a plurality of sample spots are arranged in a two-dimensional array, wherein the plurality of sample spots comprise a group of sample spots of identical samples as control spots having a predetermined positional relationship which are used for correcting spotting amount errors among sample spots belonging to other groups of sample spots having the same relative positional relationships as that of the group of control spots.
2. A microarray according to claim 1, wherein the sample spots belonging to the group of sample spots are not provided on the microarray in an adjacent manner.
3. A method for producing a microarray having a support on which a plurality of sample spots are arranged in a two-dimensional array, by repeating an operation of simultaneously spotting a plurality of samples on the support by using a spotting device provided with a plurality of pins, wherein the method comprise a step of simultaneously spotting the same samples on the support with all of the pins of the spotting device.
4. A method for correcting an inter-pin spotting amount error of a microarray produced by repeating an operation of simultaneously spotting a plurality of samples on a support by using a spotting device provided with a plurality of pins, the method comprising the steps of:

simultaneously spotting the same samples as controls on the support with all of the pins of the spotting device, where a plurality of samples are spotted on the support with the spotting device;

measuring spotting amounts of the controls spotted with the respective pins of the spotting device to obtain correction parameters for inter-pin spotting amount errors; and

correcting a measured value of each sample spot on the support by using the obtained correction parameters for the inter-pin spotting amount errors.

5. A method for correcting an inter-pin spotting amount error of a microarray according to claim 4, wherein information for identifying the pins used for immobilizing the samples to respective sample spot locations is obtained via positional information of wells on a well plate, which store the samples to be transferred to a microplate with the pins.